

NAME

CUTEst_csgrp – CUTEst tool to evaluate the sparsity pattern of the constraints gradients and gradient of objective/Lagrangian function.

SYNOPSIS

CALL CUTEst_csgrp(status, n, nnzj, lj, J_var, J_fun)

DESCRIPTION

The CUTEst_csgrp subroutine evaluates sparsity pattern used when storing the gradients of the general constraints and of either the objective function or the Lagrangian function $l(x, y) = f(x) + y^T c(x)$ corresponding to the problem decoded from a SIF file by the script *sifdecoder*.

The problem under consideration is to minimize or maximize an objective function $f(x)$ over all $x \in R^n$ subject to general equations $c_i(x) = 0$, ($i \in 1, \dots, m_E$), general inequalities $c_i^l \leq c_i(x) \leq c_i^u$ ($i \in m_E + 1, \dots, m$), and simple bounds $x^l \leq x \leq x^u$. The objective function is group-partially separable and all constraint functions are partially separable.

ARGUMENTS

The arguments of CUTEst_csgrp are as follows

status [out] - integer

the output status: 0 for a successful call, 1 for an array allocation/deallocation error, 2 for an array bound error, 3 for an evaluation error,

n [in] - integer

the number of variables for the problem,

nnzj [out] - integer

the number of nonzeros in J_var and J_fun,

lj [in] - integer

the actual declared dimensions of J_var and J_fun,

J_var [out] - integer

an array whose i-th component is the index of the variable with respect to which the derivative is taken,

J_fun [out] - integer

an array whose i-th component is the index of the problem function whose derivative is taken. J_fun(i) = 0 indicates the objective or Lagrangian function, while J_fun(i) = j > 0 indicates the j-th general constraint function.

AUTHORS

I. Bongartz, A.R. Conn, N.I.M. Gould, D. Orban and Ph.L. Toint

SEE ALSO

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads,

N.I.M. Gould, D. Orban and Ph.L. Toint,

Computational Optimization and Applications **60**:3, pp.545-557, 2014.

CUTEr (and SifDec): A Constrained and Unconstrained Testing Environment, revisited,

N.I.M. Gould, D. Orban and Ph.L. Toint,

ACM TOMS, **29**:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment,

I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint,

ACM TOMS, **21**:1, pp.123-160, 1995.

cutest_csgrp(3M), sifdecoder(1).